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Design of Built-In Tests for Robust Active Fault Detection and Isolation of Discrete Faults in

Uncertain Systems

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System Health Diagnostics in Safety-Critical Fields

Improving fault diagnostics leads to increased test rigor and guarantees to safety

Goal of system health diagnostics

□ High accuracy

Quick resolutions

Tradeoff exists between test complexity and allotted time

Cost

□ Safety







Active Model-Based Fault Detection and Isolation

MAILA

Active model-based FDI methods provide accurate, low cost diagnostics



Analysis of system health during standard operation using measurements

Active FDI

Incorporation of interruptive auxiliary input signals to improve system health analysis



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Impact of Uncertainty on Maintenance

Costly no fault found, false alarm, and non-detection events occur frequently during maintenance

Uncertainty negatively impacts system health diagnostics

Major cause of false alarms and no fault founds
Increases cost and maintenance time and decreases safety

No fault found events (NFFs) increase the potential of inserting a faulty system back into operation

- □ 30-50% of LRUs removed for maintenance in the aerospace industry are tagged as NFF [1]–[3]
- Over 90% of aircraft electronics maintenance costs can be attributed to NFFs [4]

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TI'S IO:00A.M.I GET UP! YOU'RE LATE FOR WORK! OO JUST KIDDING. JUST KIDDING

<u>Problem:</u> The absence of faults due to uncertainty during illdesigned maintenance tests is a main cause for NFFs [2], [5]

[1] P. Söderholm, "A system view of the no fault found (NFF) phenomenon," Reliab. Eng. Syst. Saf., vol. 92, pp. 1–14, Jan. 2007.

- [2] S. Khan, P. Phillips, I. Jennions, and C. Hockley, "No fault found events in maintenance engineering part 1: Current trends, implications and organizational practices," Reliab. Eng. Syst. Saf., vol. 123, pp. 183–195, Mar. 2014.
- [3] I. James, D. Lumbard, I. Willis, and J. Goble, "Investigating no fault found in the aerospace industry," in Proceedings of Annual Reliability and Maintainability Symposium (Cat. No.03CH37415), pp. 441–446, IEEE, Jan. 2003.
- Institute for Advanced Systems Engineering [4] R. Williams, J. Banner, I. Knowles, M. Dube, M. Natishan, and M. Pecht, "An investigation of 'cannot duplicate' failures," Qual. Reliab. Eng. Int., vol. 14, pp. 331–337, Sep. 1998.
 - [5] S. Khan, P. Phillips, C. Hockley, and I. Jennions, "No fault found events in maintenance engineering part 2: Root causes, technical developments and future research," Reliab. Eng. Syst. Saf., vol. 123, pp. 196–208, Mar. 2014.

Global Optimization for Built-In Test Input Design

For safety-critical systems, the conservative approach for BIT design suffices

<u>Goal:</u> Develop a maintenance test (Built-In Test (BIT)) that produces unique system responses for a fault-free system and all of its fault scenarios even at its worst-case scenario of uncertainty

<u>Method:</u> Utilize global optimization techniques to solve a max-min program, reformulated as a semi-infinite program, involving the system inputs and uncertainty

The max-min approach is often considered to be sub-optimal due to its conservative nature of "raising the floor", i.e. finding the *best* worst-case

However, for safety-critical systems with strict regulations such as in the aerospace industry, this approach is sufficient due to its guarantees



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Mathematical Formulation

Model, output, max-min, and implicit function equations

fault scenario |f|: **Model equations:** $\mathbf{f}^{[f]}(\tilde{\mathbf{x}}, \mathbf{u}, \theta_p, \theta_u, \theta_f) = \mathbf{0}, \quad \forall f \in \{0, 1, ..., N_f\}$ (1) $f^{[f]}$: governing equations $ilde{\mathbf{x}} \in ilde{X} \subset \mathbb{R}^{N_{\mathcal{X}}}:$ system states Output equations: $\mathbf{y}^{[f]} = \bar{\mathbf{x}} + \mathbf{w}$ (2) $\mathbf{u} \in U \subset \mathbb{R}^{N_u}$: inputs $\theta_p \in \Theta_p \subset \mathbb{R}^{N_{\Theta_p}}$: design parameters **Max-min program:** $\max_{\mathbf{u}\in U} \quad \min_{\theta_u\in\Theta_u, \theta_f\in\Theta_f} \quad G(\tilde{\mathbf{x}}, \mathbf{u}, \theta_p, \theta_u, \theta_f) \quad (3) \quad \theta_u\in\Theta_u \subset \mathbb{R}^{N_{\theta_u}}: \quad \text{uncertain parameters}$ $\theta_f \in \Theta_f \subset \mathbb{R}^{N_{\theta_f}}$: fault parameters s.t. $\mathbf{f}(\tilde{\mathbf{x}}, \mathbf{u}, \theta_p, \theta_u, \theta_f) = (\mathbf{f}^{[1]}, \mathbf{f}^{[2]}, ..., \mathbf{f}^{[N_f]}) = \mathbf{0}$ $\mathbf{v}^{[f]} \in Y \subset \mathbb{R}^{N_y}$: outputs $\bar{\mathbf{x}} \in \bar{X} \subseteq \tilde{X} \subset \mathbb{R}^{N_y}$: measured states Implicit function: $\tilde{\mathbf{x}} = \mathbf{x}(\mathbf{u}, \theta_p, \theta_u, \theta_f)$ exists such that $\mathbf{w} \in W \subset \mathbb{R}^{N_y}$: noise $\mathbf{f}(\mathbf{x}(\mathbf{u},\theta_p,\theta_u,\theta_f),\mathbf{u},\theta_p,\theta_u,\theta_f) = 0, \quad \forall (\mathbf{u},\theta_p,\theta_u,\theta_f) \in U \times \Theta_p \times \Theta_u \times \Theta_f$ combined equations is satisfied G: objective function

x : implicit function Θ

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Mathematical Formulation

Extensive SIP, feasibility criterion, and WCD SIP

Extensive semi-infinite program (SIP):

$$\min_{\mathbf{u}\in U, \eta\in H} -\eta$$

s.t. $g(\mathbf{x}(\mathbf{u},\theta_p,\theta_u,\theta_f),\mathbf{u},\theta_p,\theta_u,\theta_f,\eta) = \eta - G(\mathbf{x}(\mathbf{u},\theta_p,\theta_u,\theta_f),\mathbf{u},\theta_p,\theta_u,\theta_f) \le 0$ (4)
 $\forall (\theta_u,\theta_f)\in\Theta_u\times\Theta_f$

Feasibility criterion: $g(\mathbf{x}(\mathbf{u},\theta_p,\theta_u,\theta_f),\mathbf{u},\theta_p,\theta_u,\theta_f,\eta) = \eta + \eta_{feas} - \sum_{i=1}^{N_y} \sum_{j=1}^{N_f} (y_i^{[f]} - y_i^{[g]})^2$ (5)

Worst-case BIT design (WCD) SIP:

 $\min_{\mathbf{u}\in U, \ \eta\in H} -\eta$ s.t. $\eta + \eta_{feas} - \sum_{i=1}^{N_y} \sum_{f=0}^{N_f-1} \sum_{g=f+1}^{N_f} (y_i^{[f]} - y_i^{[g]})^2 \le 0$ (6) N_f : number of faults N_y : number of outputs

 $\forall (\theta_u, \theta_f) \in \Theta_u \times \Theta_f$

 $\eta \in H \subset \mathbb{R}$: SIP auxiliary variable g: Feasibility criterion η_{feas} : BIT feasibility parameter $y_i^{[f],[g]}$: i^{th} output of fault scenarios $f, g \bigotimes$

 $\mathbf{\mathbf{\Theta}}$

Worst-Case Design Algorithms

Blankenship and Falk cutting plane and Mitsos right-hand side restriction algorithms used

Worst-case BIT design algorithm [6]–[8]

- □ Initialize uncertainty
- □ Set iteration count to 1
- Begin iteration

□ Solve outer program for BIT design, analyzing all previous uncertainty sets

□ Solve inner program at BIT design,

for updated worst-case uncertainty set

Update iteration count

Examine continuation criteria

- □ If true, begin next iteration
- □ If false, end algorithm, worst-case design found U12 &

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[6] S. P. Asprey and S. Macchietto (2002). Designing robust optimal dynamic experiments. *Journal of Process Control, 12*(4), 545–556.

[7] J. W. Blankenship and J. E. Falk, Innitely constrained optimization problems, Journal of Optimization Theory and Applications, vol. 19, no. 2, pp. 261-281, 1976.

[8] Mitsos, A. Global Optimization of Semi-Infinite Programs via Restriction of the Right-Hand Side. *Optimization*. 60:10-1,1291-1308, 2011

[9] Wilhelm, Matthew; Stuber, Matthew (October 2017) Easy Advanced Global Optimization (EAGO): An Open-Source Platform for Robust and Global Optimization in Julia. Presented at the AIChE Annual Meeting in Minneapolis, MN.

Algorithm 1 SIP Max-Min Algorithm **Require:** $\theta_u^{[1]} \in \Theta_u, \theta_f^{[1]} \in \Theta_f$ 1: $K \leftarrow 1$ 2: while $\hat{\eta}^{[K]} < \eta^{[K]} \wedge K \leq K_{max}$ do $(\eta^{[K]}, \mathbf{u}^{[K]}) \leftarrow \min_{\mathbf{u} \in U, \ \eta \in H} -\eta$ 3: s.t. $\eta - G(\mathbf{x}(\mathbf{u}, \theta_p, \theta_u^{[k]}, \theta_f^{[k]}), \mathbf{u}, \theta_p, \theta_u^{[k]}, \theta_f^{[k]}) \le 0,$ $\forall k \in \{1, 2, \dots, K\}$ $(\hat{\eta}^{[K]}, \hat{\theta}^{[K+1]}_u, \hat{\theta}^{[K+1]}_f) \leftarrow$ 4: $\min_{\boldsymbol{\theta}_{u}\in\boldsymbol{\Theta}_{u},\boldsymbol{\theta}_{f}\in\boldsymbol{\Theta}_{f}} G(\mathbf{x}(\mathbf{u}^{[K]},\boldsymbol{\theta}_{p},\boldsymbol{\theta}_{u},\boldsymbol{\theta}_{f}),\mathbf{u}^{[K]},\boldsymbol{\theta}_{p},\boldsymbol{\theta}_{u},\boldsymbol{\theta}_{f})$ 5: $K \leftarrow K + 1$ 6: **end** 7: $(\mathbf{u}^{opt}, \theta_u^{opt}, \theta_f^{opt}) \leftarrow (\mathbf{u}^{[K-1]}, \theta_u^{[K]}, \theta_f^{[K]})$

[9]

Case Study: Three Tank System Description

Three tank system is a benchmark for FDI



Case Study: Different BIT Designs

Four different operating conditions were analyzed for BIT effectiveness





Case Study: Objective Function Surface

WCD lies on the intersection of the tank height constraint and the objective function G



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Case Study: Nominal BIT Design

Poor separation of anticipated outputs and distribution overlap



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Three Tank System Nominal BIT Design

Separation of anticipated outputs:

$$G(\mathbf{x}(\mathbf{u}, \theta_p, \theta_u, \theta_f), \mathbf{u}, \theta_p, \theta_u, \theta_f) = -\eta_{feas} + \sum_{i=1}^{N_y} \sum_{f=0}^{N_f-1} \sum_{g=f+1}^{N_f} (\bar{y}_i^{[f]} - \bar{y}_i^{[g]})^2 = -0.1 + 0.14 = 0.04$$

1.2

12

Case Study: Mean BIT Design

Improved separation, but violates constraints for numerous cases of uncertainty



Three Tank System Mean BIT Design

Separation of anticipated outputs:

$$G(\mathbf{x}(\mathbf{u}, \theta_{p}, \theta_{u}, \theta_{f}), \mathbf{u}, \theta_{p}, \theta_{u}, \theta_{f}) = -\eta_{feas} + \sum_{i=1}^{N_{y}} \sum_{f=0}^{N_{f}-1} \sum_{g=f+1}^{N_{f}} (\bar{y}_{i}^{[f]} - \bar{y}_{i}^{[g]})^{2} = -0.1 + 1.33 = 1.23$$

1.2

13

Case Study: Mean BIT Design w/ Conservative Constraint

Manages tank height constraint violations but results in underperformance of separation

Three Tank System Conservative Mean BIT Design



Separation of anticipated outputs:

$$G(\mathbf{x}(\mathbf{u}, \theta_{p}, \theta_{u}, \theta_{f}), \mathbf{u}, \theta_{p}, \theta_{u}, \theta_{f}) = -\eta_{feas} + \sum_{i=1}^{N_{y}} \sum_{f=0}^{N_{f}-1} \sum_{g=f+1}^{N_{f}} (\bar{y}_{i}^{[f]} - \bar{y}_{i}^{[g]})^{2} = -0.1 + 0.38 = 0.28$$

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Case Study: Worst-Case BIT Design

Maximizes separation and maintains constraint feasibility for all uncertainty scenarios



Three Tank System WCD BIT Design

Separation of anticipated outputs:

$$G(\mathbf{x}(\mathbf{u}, \theta_{p}, \theta_{u}, \theta_{f}), \mathbf{u}, \theta_{p}, \theta_{u}, \theta_{f}) = -\eta_{feas} + \sum_{i=1}^{N_{y}} \sum_{f=0}^{N_{f}-1} \sum_{g=f+1}^{N_{f}} (\bar{y}_{i}^{[f]} - \bar{y}_{i}^{[g]})^{2} = -0.1 + 0.63 = 0.53$$

1.2

15

Method developed aims at improving fault detection and isolation at the worst-case scenario(s) of uncertainty

BIT design at the worst-case scenario of uncertainty shows improvement in output separation in comparison to the nominal, mean, and conservative mean BIT designs

Global feasibility provided, guaranteeing robustness of the BIT design which is important for safety-critical systems





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[9] Wilhelm, Matthew; Stuber, Matthew (October 2017) Easy Advanced Global Optimization (EAGO): An Open-Source Platform for Robust and Global Optimization in Julia. Presented at the AIChE Annual Meeting in Minneapolis, MN. Of T



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